

<b>Notice of References Cited</b>	Application/Control No. 10/530,704	Applicant(s)/Patent Under Reexamination WU, WEI	
	Examiner Thomas F. Valone	Art Unit 2858	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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	C	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	PTO 06 - [2102] Translation, Device and Method for Measuring Electromagnetic Interference Waves, JP2002-257881, p. 1-29
	V	Silvester, Peter, Finite Elements for Electrical Engineers, Cambridge University Press, 1996, p. 10-15, 112-117
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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